

74ABT374 Octal D-Type Flip-Flop with 3-STATE Outputs

Features

- Edge-triggered D-type inputs
- Buffered positive edge-triggered clock
- 3-STATE outputs for bus-oriented applications
- Output sink capability of 64mA, source capability of 32mA
- Guaranteed output skew
- Guaranteed multiple output switching specifications
- Output switching specified for both 50pF and 250pF loads
- Guaranteed simultaneous switching, noise level and dynamic threshold performance
- Guaranteed latchup protection
- High-impedance, glitch-free bus loading during entire power up and power down cycle
- Nondestructive, hot-insertion capability

General Description

The ABT374 is an octal D-type flip-flop featuring separate D-type inputs for each flip-flop and 3-STATE outputs for bus-oriented applications. A buffered Clock (CP) and Output Enable (\overline{OE}) are common to all flip-flops.

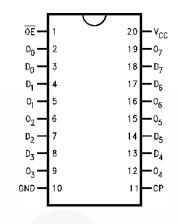
Ordering Information

Order Number	Package Number	Package Description
74ABT374CSC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide
74ABT374CSJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74ABT374CMSA	MSA20	20-Lead Shrink Small Outline Package (SSOP), JEDEC MO-150, 5.3mm Wide
74ABT374CMTC	MTC20	20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide

Device also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering number.

All packages are lead free per JEDEC: J-STD-020B standard.

Connection Diagram



Functional Description

The ABT374 consists of eight edge-triggered flip-flops with individual D-type inputs and 3-STATE true outputs. The buffered clock and buffered Output Enable are common to all flip-flops. The eight flip-flops will store the state of their individual D inputs that meet the setup and hold time requirements on the LOW-to-HIGH Clock (CP) transition. With the Output Enable (OE) LOW, the contents of the eight flip-flops are available at the outputs. When \overline{OE} is HIGH, the outputs are in a high impedance state. Operation of the OE input does not affect the state of the flip-flops.

Pin Descriptions

Pin Names	Description
D ₀ -D ₇	Data Inputs
CP	Clock Pulse Input (Active Rising Edge)
ŌĒ	3-STATE Output Enable Input (Active LOW)
O ₀ -O ₇	3-STATE Outputs

Function Table

h	nput	s	Internal	Outputs	
ŌĒ	СР	D	Q	0	Function
Н	Н	L	NC	Z	Hold
Н	Н	Н	NC	Z	Hold
Н	~	L	L	Z	Load
Н	~	Н	Н	Z	Load
L	~	L	L	L	Data Available
L	~	Н	Н	Н	Data Available
L	Н	L	NC	NC	No Change in Data
L	Н	Н	NC	NC	No Change in Data

H = HIGH Voltage Level

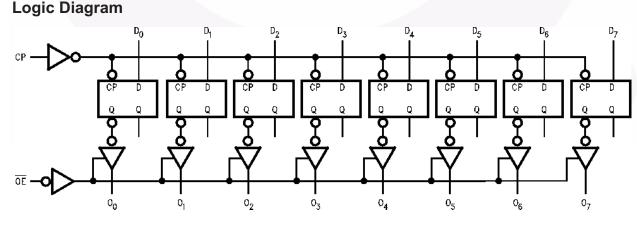
L = LOW Voltage Level

X = Immaterial

Z = High Impedance

✓ = LOW-to-HIGH Transition

NC = No Change



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

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Absolute Maximum Ratings

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.

Symbol	Parameter	Rating
T _{STG}	Storage Temperature	–65°C to +150°C
T _A	Ambient Temperature Under Bias	–55°C to +125°C
TJ	Junction Temperature Under Bias	–55°C to +150°C
V _{CC}	V _{CC} Pin Potential to Ground Pin	-0.5V to +7.0V
V _{IN}	Input Voltage ⁽¹⁾	–0.5V to +7.0V
I _{IN}	Input Current ⁽¹⁾	-30mA to +5.0mA
Vo	Voltage Applied to Any Output	
	Disabled or Power-Off State	–0.5V to 5.5V
	HIGH State	–0.5V to V _{CC}
	Current Applied to Output in LOW State (Max.)	twice the rated I _{OL} (mA)
	DC Latchup Source Current Across Common Operating Range	
	OE Pin	–150mA
	Other Pins	–500mA
	Over Voltage Latchup (I/O)	10V

Note:

1. Either voltage limit or current limit is sufficient to protect inputs.

Recommended Operating Conditions

The Recommended Operating Conditions table defines the conditions for actual device operation. Recommended operating conditions are specified to ensure optimal performance to the datasheet specifications. Fairchild does not recommend exceeding them or designing to absolute maximum ratings.

Symbol	Parameter	Rating
T _A	Free Air Ambient Temperature	–40°C to +85°C
V _{CC}	Supply Voltage	+4.5V to +5.5V
$\Delta V / \Delta t$	Minimum Input Edge Rate	
	Data Input	50mV/ns
	Enable Input	20mV/ns
	Clock Input	100mV/ns

Symbol	P	arameter	V _{cc}	Conditions	Min.	Тур.	Max.	Units
V _{IH}	Input HIGH	Voltage		Recognized HIGH Signal	2.0			V
V _{IL}	Input LOW	Voltage		Recognized LOW Signal			0.8	V
V _{CD}	Input Clam	p Diode Voltage	Min.	$I_{IN} = -18 \text{mA}$			-1.2	V
V _{OH}	Output HIG	H Voltage	Min.	$I_{OH} = -3mA$	2.5			V
				$I_{OH} = -32mA$	2.0			
V _{OL}	Output LOV	V Voltage	Min.	$I_{OL} = 64 \text{mA}$			0.55	V
I _{IH}	Input HIGH	Current	Max.	$V_{IN} = 2.7V^{(3)}$			1	μA
	,			$V_{IN} = V_{CC}$			1	
I _{BVI}	Input HIGH Test	Current Breakdown	Max.	V _{IN} = 7.0V			7	μA
IIL	Input LOW	Current	Max.	$V_{IN} = 0.5V^{(3)}$			-1	μA
				$V_{IN} = 0.0V$			-1	-
V _{ID}	Input Leakage Test		0.0	I _{ID} = 1.9μA, All Other Pins Grounded	4.75			V
I _{OZH}	Output Lea	kage Current	0-5.5V	$V_{OUT} = 2.7V, \overline{OE} = 2.0V$			10	μA
I _{OZL}	Output Lea	kage Current	0-5.5V	$V_{OUT} = 0.5V, \overline{OE} = 2.0V$			-10	μA
I _{OS}	Output Sho	ort-Circuit Current	Max.	$V_{OUT} = 0.0V$	-100		-275	mA
I _{CEX}	Output HIG	H Leakage Current	Max.	$V_{OUT} = V_{CC}$			50	μA
I _{ZZ}	Bus Draina	ge Test	0.0	$V_{OUT} = 5.5V$, All Others V_{CC} or GND			100	μA
I _{CCH}	Power Sup	ply Current	Max.	All Outputs HIGH			50	μA
I _{CCL}	Power Sup	ply Current	Max.	All Outputs LOW			30	mA
I _{CCZ}	Power Sup	ply Current	Max.	$\overline{OE} = V_{CC}$, All Others at V_{CC} or GND			50	μA
I _{CCT}	Additional	Outputs Enabled	Max.	$V_{I} = V_{CC} - 2.1V$			2.5	mA
	I _{CC} /Input	Outputs 3-STATE		Enable Input $V_I = V_{CC} - 2.1V$			2.5	mA
		Outputs 3-STATE		Data Input $V_I = V_{CC} - 2.1V$, All Others at V_{CC} or GND			2.5	mA
ICCD	Dynamic I _C	_C No Load ⁽⁴⁾	Max.	Outputs OPEN, $\overline{OE} = GND^{(2)}$, One-Bit Toggling, 50% Duty Cycle			0.30	mA/ MHz

2. For 8-bit toggling, $I_{CCD} < 0.8 \text{mA/MHz}.$

3. Guaranteed, but not tested.

DC Electrical Characteristics

SOIC package.

			Conditions C _L = 50pF,				
Symbol	Parameter	V _{cc}	$R_L = 500\Omega$	Min.	Тур.	Max.	Units
V _{OLP}	Quiet Output Maximum Dynamic V _{OL}	5.0	$T_A = 25^{\circ}C^{(4)}$		0.5	0.8	V
V _{OLV}	Quiet Output Minimum Dynamic V _{OL}	5.0	$T_A = 25^{\circ}C^{(4)}$	-1.3	-0.9		V
V _{OHV}	Minimum HIGH Level Dynamic Output Voltage	5.0	$T_A = 25^{\circ}C^{(5)}$	2.5	3.0		V
V _{IHD}	Minimum HIGH Level Dynamic Input Voltage	5.0	$T_A = 25^{\circ}C^{(6)}$	2.0	1.6		V
V _{ILD}	Maximum LOW Level Dynamic Input Voltage	5.0	$T_A = 25^{\circ}C^{(6)}$		1.3	0.8	V

Notes:

4. Max number of outputs defined as (n). n – 1 data inputs are driven 0V to 3V. One output at Low. Guaranteed, but not tested.

5. Max number of outputs defined as (n). n – 1 data inputs are driven 0V to 3V. One output HIGH. Guaranteed, but not tested.

6. Max number of data inputs (n) switching. n – 1 inputs switching 0V to 3V. Input-under-test switching: 3V to threshold (V_{ILD}), 0V to threshold (V_{ILD}). Guaranteed, but not tested.

AC Electrical Characteristics

SOIC and SSOP package.

		V	= +25° cc = +5 L = 50p	SV,		to +125°C, V to 5.5V, 50pF	$V_{CC} = 4.5$	C to +85°C, V to 5.5V, 50pF	
Symbol	Parameter	Min.	Тур.	Max.	Min.	Max.	Min.	Max.	Units
f _{MAX}	Maximum Clock Frequency	150	200		150		150		MHz
t _{PLH}	Propagation Delay	2.0	3.2	5.0	1.4	6.6	2.0	5.0	ns
t _{PHL}	CP to O _n	2.0	3.3	5.0	2.0	7.6	2.0	5.0	
t _{PZH}	Output Enable Time	1.5	3.1	5.3	0.8	5.7	1.5	5.3	ns
t _{PZL}		1.5	3.1	5.3	1.5	7.2	1.5	5.3	
t _{PHZ}	Output Disable Time	1.5	3.6	5.4	1.3	7.2	1.5	5.4	ns
t _{PLZ}		1.5	3.4	5.4	1.0	7.0	1.5	5.4	

AC Operating Requirements

		$\begin{array}{l} T_A = +25^\circ C \\ V_{CC} = +5.0V \\ C_L = 50 p F \end{array}$		$ \begin{array}{c} T_{A} = -55^{\circ}C \ to \ +125^{\circ}C \\ V_{CC} = 4.5V \ to \ 5.5V \\ C_{L} = 50pF \end{array} $		$\label{eq:TA} \begin{array}{l} \textbf{T}_{A} = -40^{\circ} \textbf{C} \text{ to } +85^{\circ} \textbf{C} \\ \textbf{V}_{CC} = 4.5 \textbf{V} \text{ to } 5.5 \textbf{V} \\ \textbf{C}_{L} = 50 \textbf{pF} \end{array}$		
Symbol	Parameter	Min.	Max.	Min.	Max.	Min.	Max.	Units
t _S (H)	Setup Time, HIGH or LOW D _n to CP	1.5		2.5		1.0		ns
t _S (L)		1.5		2.5		1.5		
t _H (H)	Hold Time, HIGH or LOW	1.0		2.5		1.0		ns
t _H (L)	D _n to CP	1.0		2.5		1.0		
t _W (H)	Pulse Width, CP HIGH or	3.0		3.3		3.0		ns
t _W (L)	LOW	3.0		3.3		3.0		

Extended AC Electrical Characteristics

SOIC package.

		C _L =	V to 5.5V, 50pF, tputs	$T_{A} = -40^{\circ}$ $V_{CC} = 4.$ $C_{L} = 2$	°C to +85°C, 5V to 5.5V, 250pF ⁽⁸⁾	V _{CC} = 4.5 C _L = 2 8 Ou	C to +85°C, 5V to 5.5V, 250pF, itputs hing ⁽⁹⁾	
Symbol	Parameter	Min	Max	Min	Max	Min	Max	Units
t _{PLH}	Propagation	1.5	5.7	2.0	7.8	2.0	10.0	ns
t _{PHL}	Delay CP to O _n	1.5	5.7	2.0	7.8	2.0	10.0	
t _{PZH}	Output Enable	1.5	6.2	2.0	8.0	2.0	10.5	ns
t _{PZL}	Time	1.5	6.2	2.0	8.0	2.0	10.5	
t _{PHZ}	Output Disable	1.0	5.5		(10)	(1	0)	ns
t _{PZL}	Time	1.0	5.5					

Notes:

- This specification is guaranteed but not tested. The limits represent propagation delay with 250pF load capacitors in place of the 50pF load capacitors in the standard AC load. This specification pertains to single output switching only.
- 9. This specification is guaranteed but not tested. The limits represent propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.) with 250pF load capacitors in place of the 50pF load capacitors in the standard AC load.
- 10. The 3-STATE delay Time is dominated by the RC network (500Ω, 250pF) on the output and has been excluded from the datasheet.

^{7.} This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.).

Skew⁽¹⁵⁾

SOIC package.	SOIC	package.	
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		$T_{A} = -40^{\circ}C \text{ to } +85^{\circ}C$ $V_{CC} = 4.5V - 5.5V$ $C_{L} = 50 \text{ pF}$ 8 Outputs Switching ⁽¹¹⁾	$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$ $V_{CC} = 4.5V - 5.5V$ $C_L = 250 \text{ pF}$ 8 Outputs Switching ⁽¹²⁾	
Symbol	Parameter	Max.	Max.	Units
t _{OSHL} ⁽¹³⁾	Pin to Pin Skew, HL Transitions	1.0	1.8	ns
t _{OSLH} ⁽¹³⁾	Pin to Pin Skew, LH Transitions	1.0	1.8	ns
t _{PS} ⁽¹²⁾	Duty Cycle, LH–HL Skew	1.8	4.3	ns
t _{OST} ⁽¹³⁾	Pin to Pin Skew, LH/HL Transitions	2.0	4.3	ns
t _{PV} ⁽¹⁴⁾	Device to Device Skew, LH/HL Transitions	2.5	4.6	ns

Notes:

11. This specification is guaranteed but not tested. The limits represent propagation delays with 250pF load capacitors in place of the 50pF load capacitors in the standard AC load.

- 12. This describes the difference between the delay of the LOW-to-HIGH and the HIGH-to-LOW transition on the same pin. It is measured across all the outputs (drivers) on the same chip, the worst (largest delta) number is the guaranteed specification. This specification is guaranteed but not tested.
- 13. Skew is defined as the absolute value of the difference between the actual propagation delays for any two separate outputs of the same device. The specification applies to any outputs switching HIGH-to-LOW (t_{OSHL}), LOW-to-HIGH (t_{OSLH}), or any combination switching LOW-to-HIGH and/or HIGH-to-LOW (t_{OST}). This specification is guaranteed but not tested.
- 14. Propagation delay variation for a given set of conditions (i.e., temperature and V_{CC}) from device to device. This specification is guaranteed but not tested.
- 15. This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.).

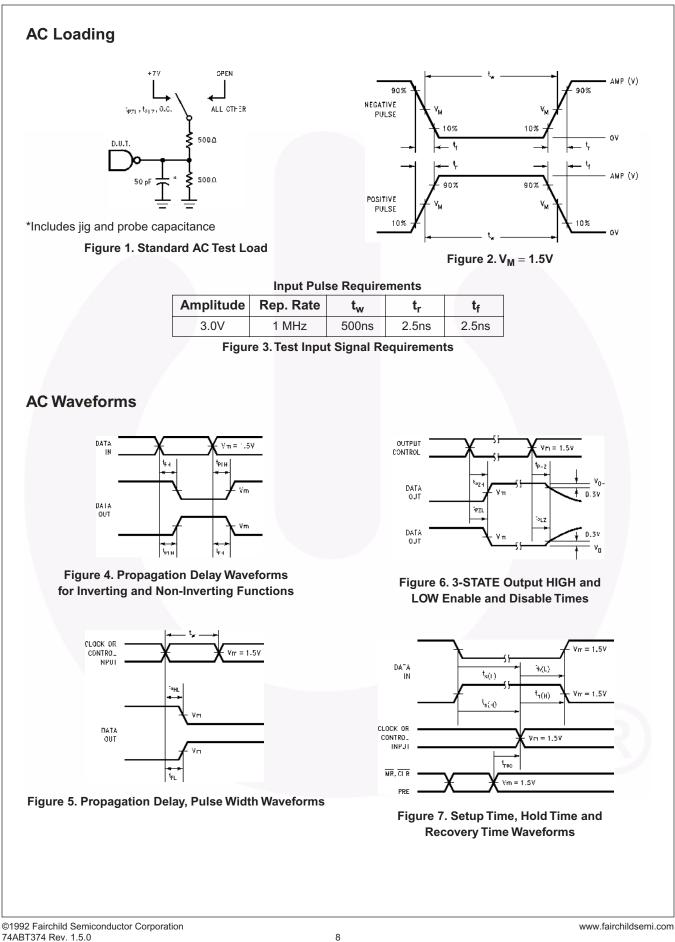
Capacitance

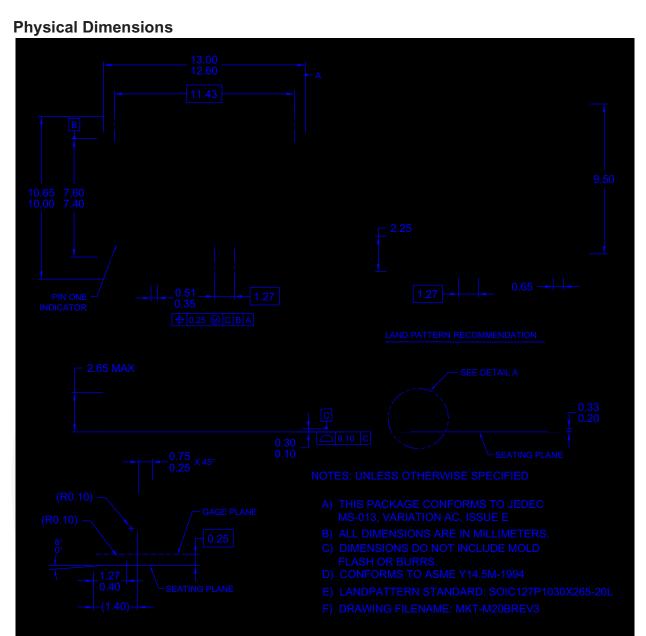
Symbol	Parameter	Conditions T _A = 25°C	Тур.	Units
C _{IN}	Input Capacitance	$V_{CC} = 0V$	5.0	pF
C _{OUT} ⁽¹⁶⁾	Output Capacitance	$V_{CC} = 5.0V$	9.0	pF

Note:

16. C_{OUT} is measured at frequency f = 1MHz, per MIL-STD-883, Method 3012.









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Physical Dimensions (Continued)

Figure 11. 20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide

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